

Application/Control No.	Applicant(s)/Patent under Reexamination	
09/940,035	LEE ET AL.	
Examiner	Art Unit	
Minh Dinh	2132	

	SEARCHED			
Class	Subclass	Date	Examiner	
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TNI	INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner		
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SEARCH NOT (INCLUDING SEARCH)
	DATE	EXMR
713/165,167,169,185 726/27,29-30 705/51,57-58 380/201-202,279,281-285 (text search only for all - see search history printout)	5/5/2006	MD
EAST (US-PGPUB, USPAT, EPO, JPO, DERWENT, IBM_TDB) - see search history printout	5/5/2006	MD
Inventor Name Search	5/5/2006	MD
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